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| No. | Test Item | Testing conditions | Conditions of acceptability | Number of samples | Number of failures |
|-----|---|---|---|-------------------|--------------------|
| 1 | Heat cycle test | (1) -40°C ~ 125°C 30minutes each (2) 200cycles | (1)No degradation of electric characteristics after test. (2)No crack at solder joint. | 3 | 0 |
| 2 | High temperature/ High humidity bias test | (1) Ta=85°C, RH=85% (2) At rated input (3) Load 0% (4) 1000hours | (1)No degradation of electric characteristics after test. | 3 | 0 |
| 3 | Vibration test | (1) f=10~55Hz, 19.6m/s ² (2G) (2) 3minutes period (3) 60minutes each X, Y and Z axis | (1)No degradation of electric characteristics after test. (2)No crack at solder joint. (3)No mechanical damage of appearance. | 3 | 0 |
| 4 | Impact test | (1) 196.1m/s ² (20G), 11ms (2) Once each X, Y and Z axis | (1)No degradation of electric characteristics after test. (2)No crack at solder joint. (3)No thermal damage of appearance. | 3 | 0 |
| 5 | Static electricity immunity test | (1) Applied voltage ±8kV (2) At rated input and load (3) Testing circuitry Fig.1 | (1)No protection circuit fail. (2)No output voltage drop due to control (3)No any other function fail. | 1 | 0 |